

INCITS 322-2015

American National Standard

*for Information Technology –
Card Durability Test Methods*

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INCITS 322-2015

Revision of
INCITS 322-2008

American National Standard
for Information Technology –

Card Durability Test Methods

Secretariat

Information Technology Industry Council

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American National Standards Institute, Inc.

American National Standard

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Foreword (This foreword is not part of American National Standard INCITS 322-2015.)

This standard provides an agreed upon set of set of test methods which contain specific procedures to be followed. The acceptance or rejection criteria of identification cards, based on test results from these durability test methods, are not within the scope of work of this standard.

The precision and bias of test results obtained from a given test method are influenced by a host of variables. The major sources of this variation are contributed by test method, test design, operator, measurement technique, equipment, calibration, environment and materials variation. Round robin test results from many of the test methods are available upon request.

The test method development has attempted to minimize the variation that the test methods might contribute. The test design should consider randomization of test materials, replication and the skillful grouping of test materials. Each operator must be diligent in the use of good testing practices in order to minimize the operator's contributions to the test variability.

Durability acceptance criteria as stated in ISO/IEC 7810 3rd edition - 2003 Physical characteristics - Clause 8.7: "Durability of the card is not established in this International Standard. It is based on a mutual agreement between the card issuer and the supplier." Accordingly, the card issuer and supplier need to agree to which durability test method, contained herein, is relevant for the given card application.

INCITS B10.11 Task Group on Physical Characteristics and Test Methods has established the following process steps for generating this standard:

- Step 1: Identify existing ID card durability problems experienced in field performance.
- Step 2: Identify potential test methods that relate to the durability concern.
- Step 3: Select a team leader, with other experts, to coordinate proposed test methods in given categories (i.e. abrasion resistance, Peel Strength, and adhesion).
- Step 4: Presentation of a new Test Method for consideration.
- Step 5: Task Group discussion of the proposal. Determination of whether it "fits" within the Scope of Work.
- Step 6: Proposal is given "Pending Status" for determination at the next meeting. At the next meeting, the proposal is either "Accepted in Principal" or rejected. If accepted, the proposal is incorporated into the working paper for further discussion and possible modification at succeeding meetings.
- Step 7: Testing is conducted and results reported to "validate" the test technique and/or to resolve technical issues.
- Step 8: The Test Method status becomes "Accepted for Publication" after all issues have been resolved.

These test methods may suggest use of materials or test equipment, which are trade-names of a product supplied by a specific manufacturer. This information is given for the convenience of users of this American National Standard and does not constitute an endorsement by ANSI or INCITS of the product named. Equivalent products may be used if they can be shown to lead to the same results.

This standard was developed by Technical Committee B10 of Accredited Standards Committee INCITS during 2002 – 2006. The standards approval process started in 2006. This document includes annexes that are informative and are not considered part of the standard.

Requests for interpretation, suggestions for improvement or addenda, or defect reports are welcome. They should be sent to InterNational Committee for Information Technology Standards (INCITS), ITI, 1101 K Street, NW, Suite 610, Washington, DC 20005.

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National Institute of Standards & Technology.....	Michael Hogan Sal Francomacaro (Alt.) Wo Chang (Alt.)
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Purdue University.....	Stephen Elliott Kevin O'Connor (Alt.)
Telecommunications Industry Association (TIA).....	Florence Otieno Stephanie Montgomery (Alt.)
US Department of Defense.....	Dennis Devera Leonard Levine (Alt.)
US Department of Homeland Security.....	Peter Shebell Gregg Piermarini (Alt.) Juan Gonzalez (Alt.)

Technical Committee B10 on ID Cards and Related Devices, which reviewed this standard, had the following members:

Brian Beech, Chair
Gene Meier, International Representative

<i>Organization Represented</i>	<i>Name of Representative</i>
AAMVA.....	Geoff Slagle Michael Calvin (Alt.)
ABnote North America.....	Joe Mandile
CFC International.....	Dan Szumski Roger Strasemeier (Alt.)
CPI Card Group.....	Jim Colleran Jeff Licht (Alt.) Barry Mosteller (Alt.)
Cubic Transportation Systems, Inc.	Walt Bonneau, Jr. Jon Macklin (Alt.)
Discover Card.....	Catherine Madison Cheryl Mish (Alt.) Lakshmi Ramanathan (Alt.) Michelle Zhang (Alt.)
Eclipse Laboratories.....	Brad Paulson Kevin Tall (Alt.)
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Exponent, Inc.	Brad McGoran Ellick Chan (Alt.) John Fessler (Alt.) Christian Page (Alt.)
Fall Hill Associates LLC.....	Barry Kefauver
Gemalto.....	Michel Escalant Drew Anders (Alt.)

<i>Organization Represented</i>	<i>Name of Representative</i>
Giesecke & Devrient.....	Steven Spence Myeong Choi (Alt.) John Deshpande (Alt.) Ji Lee (Alt.) Carla Limerick (Alt.) Thomas Palsherm (Alt.) Eric Verostek (Alt.)
HID Global	Victoria Wiggins Christopher Dyball (Alt.) Traci Johnson (Alt.)
ID Technology Partners, Inc.....	Gerald Smith David Auman (Alt.) Gilles Lisimaque (Alt.)
Infineon Technologies	Mark Stafford Jurijus Cizas (Alt.) Shrinath Eswaramally (Alt.)
International Card Manufacturers Association.....	David Tushie
Kurz Transfer Products.....	Steve Schwartz
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Mount Airey Group, Inc.....	Bill Russell Paul Townsend (Alt.)
NIST	Sal Francomacaro William Barker (Alt.) Hildegard Ferraiolo (Alt.) Ketan Mehta (Alt.) Annie Sokol (Alt.)
NXP Semiconductors	Mike Zercher
Oberthur Technologies.....	Christophe Goyet Joe Blossic (Alt.)
Peter T. Barry Company.....	Peter Barry (Liaison)
Q-CARD	Terry Schindler
Security Industry Association	Joe Gittens
UATP.....	Patrick Macy
U.S. Department of Defense - Defense Manpower Data Center	Bob Gilson Tim Baldridge (Alt.) Jonathan Shu (Alt.)
VISA	Kristina Breen Ken Sippola (Alt.) Dori Skelding (Alt.) Mustafa Top (Alt.)
WidePoint Corporation	Daniel Turissini

Task Group B10.11 on Physical Characteristics and Test Methods, which developed and reviewed this standard, had the following members:

Terry Schindler, Chair
Gene Meier, Secretary

<i>Organization Represented</i>	<i>Name of Representative</i>
ABnote North America	Joe Mandile
Bayer Material Science	Chris Cooper
CFC International	Dan Szumski
	Roger Strasmeier (Alt.)
CPI Card Group	Jim Colleran
	Jeff Licht (Alt.)
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	Joe Picardi (Alt.)
Oberthur Technologies	Joe Blossic
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	Sean Kelly (Alt.)
Q-CARD	Terry Schindler
VISA	Kristina Breen
	Ken Sippola (Alt.)
	Dori Skelding (Alt.)

American National Standard
for Information Technology –

Card Durability Test Methods

1 SCOPE

This American National Standard describes Test Methods for the evaluation of Identification (ID) card durability. An ID card is defined as a card identifying its holder and issuer which may carry data required as input for the intended use of the card.

These test methods are to be used by card issuers, card manufacturers and card component suppliers to make comparisons of ID card performance. These test methods do not imply a specific correlation to end use field performance or a given card service life. However, these test methods may be useful for ranking or comparing the relative durability of ID cards.

Results obtained by use of these test methods should not be represented as equivalent to field use performance or an absolute index of ultimate card service unless a degree of quantitative correlation has been established for the ID card material construction in question.

These test methods do not possess and do not constitute requirements for ID cards in general. The reader is referred to specific application standards for performance requirements and acceptance criteria. It is the responsibility of card issuers and their suppliers to decide which attributes are required for card performance in a given card application and to mutually agree which test methods may be appropriate to assess card performance.

These test methods may involve the use of hazardous materials, operations and equipment. This standard does not purport to address all safety problems associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of local and federal regulatory limitations prior to use.

2 NORMATIVE REFERENCES

The following references constitute provisions of this American National Standard on Test Methods. At the time of publication, the editions indicated were valid. All references are subject to revision and interested parties are encouraged to access the impact of updated revisions.

Copies of the following documents can be obtained from ANSI: Approved ANSI standards, approved and draft international standards (ISO, IEC), and approved foreign standards (including JIS and DIN). For further information, contact ANSI Customer Service Department at 212-642-4900 (phone), 212-302-1286 (fax) or via the World Wide Web at <http://www.ansi.org>.

Document	Title	Subclause Referenced
ANSI/INCITS.182-1990 (R2002)	<i>Guideline for Barcode Print Quality</i> ¹	5.9, 5.13
ANSI/ISO/IEC 7810:2003	<i>Identification cards – Physical characteristics</i> ¹	4.5

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